

**Notice of References Cited**

Application/Control No.

10/577,325

Applicant(s)/Patent Under  
Reexamination  
NAKAMURA ET AL.

Examiner

Matthew W. Such

Art Unit

2891

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,720,572	04-2004	Jackson et al.	257/40
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.